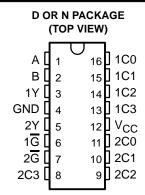
74AC11153 DUAL 1-OF-4 DATA SELECTOR/MULTIPLEXER

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- Permits Multiplexing From N Lines to 1 Line
- Performs Parallel-to-Serial Conversion
- Strobe (Enable) Line Provided for Cascading (N Lines to N Lines)
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs



description

This data selector/multiplexer contains inverters and drivers to supply full binary decoding data selection to the AND-OR gates. Separate strobe inputs (\overline{G}) are provided for each of the two four-line sections.

The 74AC11153 is characterized for operation from -40°C to 85°C.

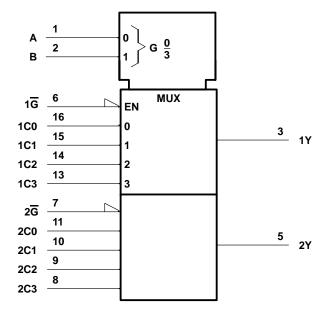
FUNCTION TABLE

INPUTS						OTDODE	QUITDUT		
SELECT		DATA				STROBE G	OUTPUT Y		
В	Α	C0	C1	C2	C3	Ŭ	•		
Х	Х	Χ	Х	Х	Х	Н	L		
L	L	L	X	X	X	L	L		
L	L	Н	Χ	Χ	X	L	Н		
L	Н	Χ	L	X	X	L	L		
L	Н	Χ	Н	X	Х	L	Н		
Н	L	Χ	Χ	L	Х	L	L		
Н	L	Χ	X	Н	X	L	Н		
Н	Н	Χ	Χ	X	L	L	L		
Н	Н	Χ	X	X	Н	L	Н		

H = high level, L = low level, X = irrelevant

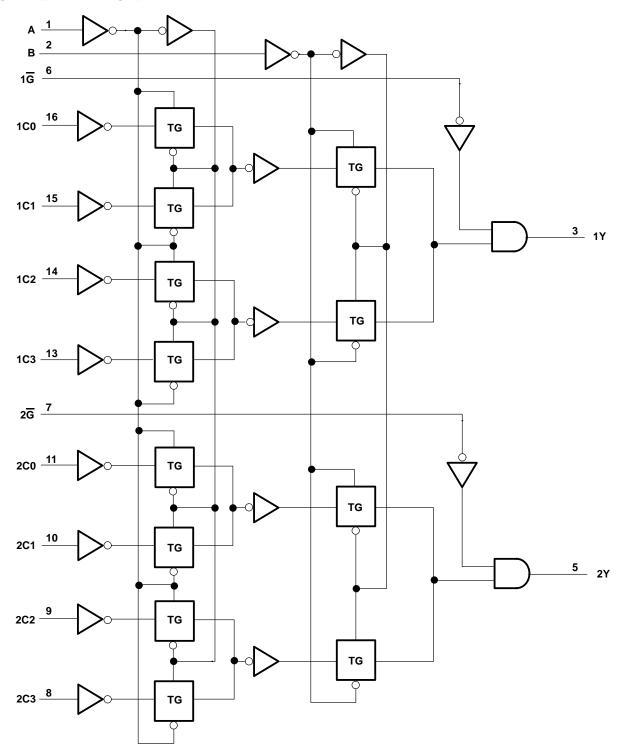
Texas VI

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	$-0.5\ V$ to 7 V
Input voltage range, V _I (see Note 1)	\dots -0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±100 mA
Storage temperature range	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		3	5	5.5	V
VIH VIL VI VO		V _{CC} = 3 V	2.1			
	High-level input voltage	V _{CC} = 4.5 V	3.15			V
		V _{CC} = 5.5 V	3.85			
		V _{CC} = 3 V			0.9	
V _{IL}	Low-level input voltage	V _{CC} = 4.5 V			1.35	V
		V _{CC} = 5.5 V			1.65	
٧ı	Input voltage		0		VCC	V
٧o	Output voltage		0		Vcc	V
		V _{CC} = 3 V			-4	
ЮН	High-level output current	V _{CC} = 4.5 V			-24	mA
		V _{CC} = 5.5 V			-24	
		V _{CC} = 3 V			12	
lOL	Low-level output current	V _{CC} = 4.5 V			24	mA
		V _{CC} = 5.5 V			24	
Δt/Δν	Input transition rise or fall rate		0		10	ns/V
T _A	Operating free-air temperature		-40		85	°C



NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Voc	T _A = 25°C			MIN	MAY	UNIT
FARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	IVIIIV	0.1 0.1 0.1 0.44 0.44 1.65 ±1 80	ONIT
	I _{OH} = - 50 μA	3 V	2.9			2.9		
		4.5 V	4.4			4.4		
		5.5 V	5.4			5.4		
Vон	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.48		V
		4.5 V	3.94			3.8		
	I _{OH} = -24 mA	5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	I _{OL} = 50 μA	3 V			0.1		0.1	
		4.5 V			0.1		0.1	
		5.5 V			0.1		0.1	
VOL	I _{OL} = 12 mA	3 V			0.36		0.1 0.1 0.44 0.44 1.65 ±1	V
	la. 24 mA	4.5 V			0.36		0.44	
	I _{OL} = 24 mA	5.5 V			0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
lį	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80	μΑ
Ci	$V_I = V_{CC}$ or GND	5 V		3.5				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	то	T _A = 25°C			MIN	MAX	UNIT
PARAMETER		(OUTPUT)	MIN	TYP	MAX	IVIIIV	IVIAA	UNIT
^t PLH	A or B	V	2.3	7.4	9.5	2.3	10.5	ns
^t PHL		I	2.6	7.6	9.9	2.6	11	115
^t PLH	Data (Any C)	V	2.3	6.9	8.4	2.3	9.5	20
^t PHL		ī	2.6	7.1	8.7	2.6	9.9	ns
^t PLH	G	V	1.8	5.3	6.7	1.8	7.5	ns
^t PHL	G	ı	1	5.2	7.2	1	8.5	110

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

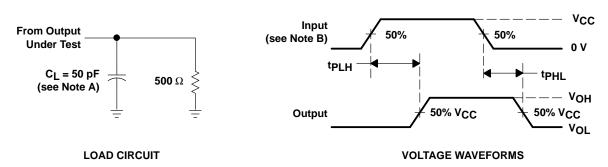
PARAMETER	FROM	то	T,	<u> </u> = 25°C	;	MIN	MAX	UNIT
FARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV		ONIT
t _{PLH}	A or B	V	2	4.7	6.8	2	7.6	ns
^t PHL		ı	1.6	5.5	7.7	1.6	8.6	115
^t PLH	Data (Any C)	V	1.9	4.5	6.1	1.9	6.9	nc
^t PHL		1	2.5	5	6.9	2.5	7.8	ns
t _{PLH}	G	V	1.4	3.6	5.1	1.4	5.7	nc
^t PHL		1	1.8	4.3	5.8	1.8	6.7	ns

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operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	30	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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